Integrated Device Technology, Inc.

3.3V CMOS OCTAL D REGISTERS (3-STATE)

IDT54/74FCT3374/A
IDT54/74FCT3534/A
IDT54/74FCT3574/A
PRODUCT PREVIEW

FEATURES:

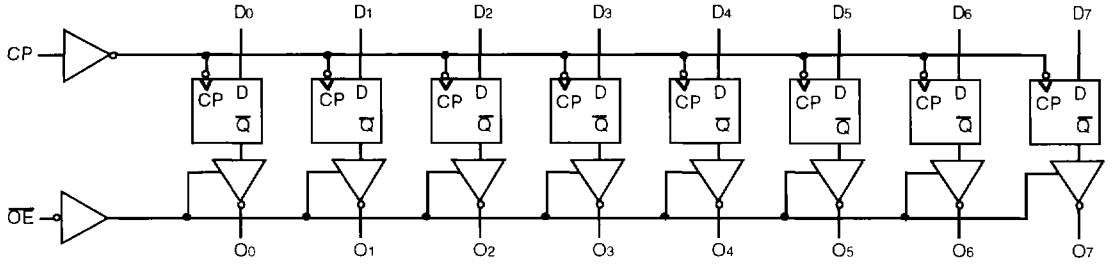
- 0.5 MICRON CMOS Technology
- ESD > 2000V per MIL-STD-883, Method 3015; > 200V using machine model (C = 200pF, R = 0)
- 25 mil Center SSOP Packages
- Extended commercial range of –40°C to +85°C
- Vcc = 3.3V ±0.3V, Normal Range or Vcc = 2.7V to 3.6V, Extended Range
- CMOS power levels (10µW typ. static)
- Rail-to-Rail output swing for increased noise margin
- Military product compliant to MIL-STD-883, Class B

DESCRIPTION:

The IDT54/74FCT3374/A, IDT54/74FCT3534/A and IDT54/74FCT3574/A are 8-bit registers built using an advanced dual metal CMOS technology. These registers consist of eight D-type flip-flops with a buffered common clock and buffered 3-state output control. When the output ($\overline{OE}$) input is LOW, the eight outputs are enabled. When the $\overline{OE}$ input is HIGH, the outputs are in the high-impedance state.

Input data meeting the set-up and hold time requirements of the D inputs is transferred to the O outputs on the LOW-to-HIGH transition of the clock input.

FUNCTIONAL BLOCK DIAGRAM IDT54/74FCT3374 AND IDT54/74FCT3574



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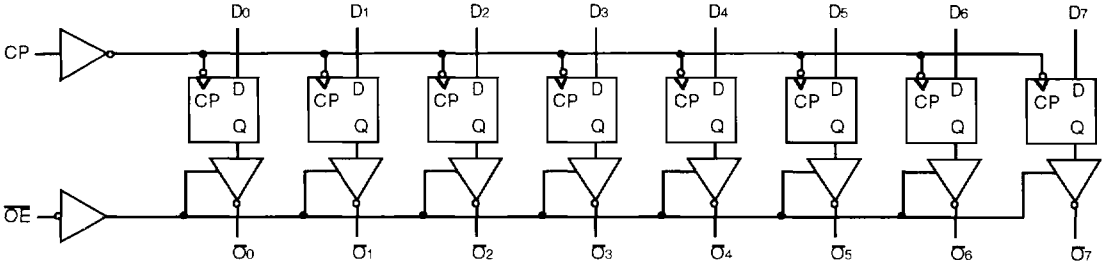
FUNCTIONAL BLOCK DIAGRAM IDT54/74FCT3534



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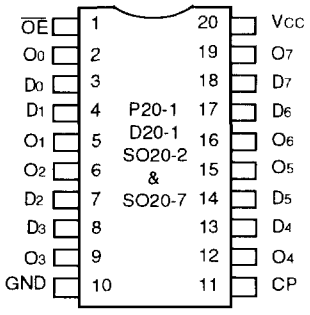
PIN CONFIGURATIONS

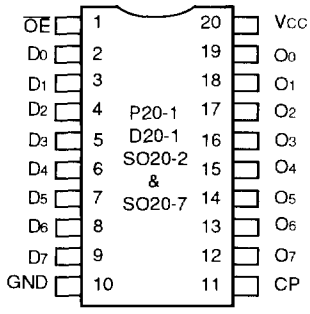
FCT3374



DIP/SOIC/SSOP TOP VIEW

3095 drw 02

FCT3574



DIP/SOIC/SSOP TOP VIEW

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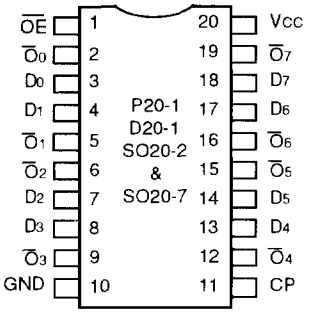
FCT3534



DIP/SOIC/SSOP TOP VIEW

3095 drw 04

PIN DESCRIPTION

Pin Names	Description
D_N	D flip-flop data inputs
CP	Clock Pulse for the register. Enters data on LOW-to-HIGH transition.
O_N	3-state outputs, (true)
$\overline{O}_N$	3-state outputs, (inverted)
$\overline{OE}$	Active LOW 3-state Output Enable input

3095 tbl 01

FUNCTION TABLE (1)

	Inputs			3534		3374/3574	
				Outputs	Internal	Outputs	Internal
Function	$\overline{OE}$	CP	D_N	$\overline{O}_N$	Q_N	O_N	$\overline{Q}_N$
HI-Z	H	L	X	Z	NC	Z	NC
	H	H	X	Z	NC	Z	NC
LOAD REGISTER	L	↑	L	H	L	L	H
	L	↑	H	L	H	H	L
	H	↑	L	Z	L	Z	H
	H	↑	H	Z	H	Z	L

3095 tbl 02

NOTE:
1. H = HIGH Voltage Level
   L = LOW Voltage Level
   X = Don't Care
   Z = High Impedance
   NC = No Change
   ↑ = LOW-to-HIGH transition

ABSOLUTE MAXIMUM RATINGS(1)

Symbol	Rating	Commercial	Military	Unit
V_{TERM}(2)	Terminal Voltage with Respect to GND	–0.5 to +4.6	–0.5 to +4.6	V
V_{TERM}(3)	Terminal Voltage with Respect to GND	–0.5 to +7.0	–0.5 to +7.0	V
V_{TERM}(4)	Terminal Voltage with Respect to GND	–0.5 to V_{CC} + 0.5	–0.5 to V_{CC} + 0.5	V
T_A	Operating Temperature	–40 to +85	–55 to +125	°C
T_{BIAS}	Temperature Under Bias	–55 to +125	–65 to +135	°C
T_{STG}	Storage Temperature	–55 to +125	–65 to +150	°C
P_T	Power Dissipation	1.0	1.0	W
I_{OUT}	DC Output Current	–60 to +60	–60 to +60	mA

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NOTES:
1. Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.
2. Vcc terminals.
3. Input terminals.
4. Output and I/O terminals.

CAPACITANCE (T_A = +25°C, f = 1.0MHz)

Symbol	Parameter(1)	Conditions	Typ.	Max.	Unit
C_{IN}	Input Capacitance	V_{IN} = 0V	3.5	6.0	pF
C_{OUT}	Output Capacitance	V_{OUT} = 0V	4.0	8.0	pF

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NOTE:
1. This parameter is measured at characterization but not tested.

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DC ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE

Following Conditions Apply Unless Otherwise Specified:
Commercial: T_A = –40°C to +85°C, V_{CC} = 2.7V to 3.6V; Military: T_A = –55°C to +125°C, V_{CC} = 2.7V to 3.6V

Symbol	Parameter	Test Conditions[1]		Min.	Typ.[2]	Max.	Unit
V_{IH}	Input HIGH Level (Input pins)	Guaranteed Logic HIGH Level		2.0	—	5.5	V
	Input HIGH Level (I/O pins)			2.0	—	V_{CC}+0.5	
V_{IL}	Input LOW Level (Input and I/O pins)	Guaranteed Logic LOW Level		–0.5	—	0.8	V
I_{IH}	Input HIGH Current (Input pins)[6]	V_{CC} = Max.	V_I = 5.5V	—	—	±1	µA
	Input HIGH Current (I/O pins)[6]		V_I = V_{CC}	—	—	±1	
I_{IL}	Input LOW Current (Input pins)[6]		V_I = GND	—	—	±1	
	Input LOW Current (I/O pins)[6]		V_I = GND	—	—	±1	
I_{OZH}	High Impedance Output Current	V_{CC} = Max.	V_O = V_{CC}	—	—	±1	µA
I_{OZL}	(3-State Output pins)[6]		V_O = GND	—	—	±1	
V_{IK}	Clamp Diode Voltage	V_{CC} = Min., I_{IN} = –18mA		—	–0.7	–1.2	V
I_{ODH}	Output HIGH Current	V_{CC} = 3.3V, V_{IN} = V_{IH} or V_{IL}, V_O = 1.5V[3]		–36	–60	–110	mA
I_{ODL}	Output LOW Current	V_{CC} = 3.3V, V_{IN} = V_{IH} or V_{IL}, V_O = 1.5V[3]		50	90	200	mA
V_{OH}	Output HIGH Voltage	V_{CC} = Min.	I_{OH} = –0.1mA	V_{CC}–0.2	—	—	V
		V_{IN} = V_{IH} or V_{IL}	I_{OH} = –3mA	2.4	3.0	—	
		V_{CC} = 3.0V V_{IN} = V_{IH} or V_{IL}	I_{OH} = –6mA MIL. I_{OH} = –8mA COM'L.	2.4[5]	3.0	—	
V_{OL}	Output LOW Voltage	V_{CC} = Min.	I_{OL} = 0.1mA	—	—	0.2	V
		V_{IN} = V_{IH} or V_{IL}	I_{OL} = 16mA	—	0.2	0.4	
			I_{OL} = 24mA	—	0.3	0.5	
I_{OS}	Short Circuit Current[4]	V_{CC} = Max., V_O = GND[3]		–60	–135	–240	mA
V_H	Input Hysteresis	—		—	150	—	mV
I_{CCL} I_{CCH}	Quiescent Power Supply Current	V_{CC} = Max., V_{IN} = GND or V_{CC}	COM'L.	—	0.1	10	µA
I_{CCZ}			MIL.	—	0.1	100	

3095 lnk 05

NOTES:

1. For conditions shown as Max. or Min., use appropriate value specified under Electrical Characteristics for the applicable device type.
2. Typical values are at Vcc = 3.3V, +25°C ambient.
3. Not more than one output should be tested at one time. Duration of the test should not exceed one second.
4. This parameter is guaranteed but not tested.
5. V_{OH} = V_{CC} –0.6V at rated current.
6. The test limits for this parameter is ± 5µA at T_A = –55°C.

POWER SUPPLY CHARACTERISTICS

Symbol	Parameter	Test Conditions[1]		Min.	Typ.[2]	Max.	Unit
ΔI_{CC}	Quiescent Power Supply Current	V_{CC} = Max.	V_{IN} = V_{CC} −0.6V[3]				mA
I_{CCD}	Dynamic Power Supply Current[4]	V_{CC} = Max. Outputs Open $\overline{OE}$ = GND 50% Duty Cycle One Input Toggling	V_{IN} = V_{CC} V_{IN} = GND				µA/ MHz
I_C	Total Power Supply Current[6]	V_{CC} = Max. Outputs Open f_{CP} = 10MHz 50% Duty Cycle $\overline{OE}$ = GND f_i = 5MHz 50% Duty Cycle One Bit Toggling	V_{IN} = V_{CC} V_{IN} = GND				mA
			V_{IN} = V_{CC} −0.6V V_{IN} = GND				
		V_{CC} = Max. Outputs Open f_{CP} = 10MHz 50% Duty Cycle $\overline{OE}$ = GND f_i = 2.5MHz 50% Duty Cycle Eight Bits Toggling	V_{IN} = V_{CC} V_{IN} = GND				
			V_{IN} = V_{CC} −0.6V V_{IN} = GND				

3095 tbl 06

NOTES:

1. For conditions shown as max. or min., use appropriate value specified under Electrical Characteristics for the applicable device type.
2. Typical values are at V_{CC} = 3.3V, +25°C ambient.
3. Per TTL driven input; all other inputs at V_{CC} or GND.
4. This parameter is not directly testable, but is derived for use in Total Power Supply Calculations.
5. Values for these conditions are examples of the I_{CC} formula. These limits are guaranteed but not tested.
6. $I_C = I_{QUIESCENT} + I_{INPUTS} + I_{DYNAMIC}$
   $I_C = I_{CC} + \Delta I_{CC} D_H N_T + I_{CCD} (f_{CP} N_{CP}/2 + f_i N_i)$
   I_{CC} = Quiescent Current (I_{CCL}, I_{CCH} and I_{CCZ})
   ΔI_{CC} = Power Supply Current for a TTL High Input
   D_H = Duty Cycle for TTL Inputs High
   N_T = Number of TTL Inputs at D_H
   I_{CCD} = Dynamic Current Caused by an Input Transition Pair (HLH or LHL)
   f_{CP} = Clock Frequency for Register Devices (Zero for Non-Register Devices)
   N_{CP} = Number of Clock Inputs at f_{CP}
   f_i = Input Frequency
   N_i = Number of Inputs at f_i

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SWITCHING CHARACTERISTICS OVER OPERATING RANGE[3]

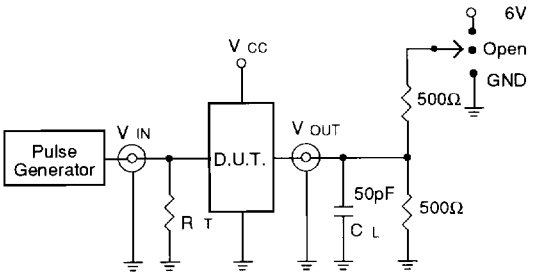
Symbol	Parameter	Conditions[1]	FCT3374/3534/3574				FCT3374A/3534A/3574A				Unit
			Com'l.		Mil.		Com'l.		Mil.		
			Min.[2]	Max.	Min.[2]	Max.	Min.[2]	Max.	Min.[2]	Max.	
t_{PLH} t_{PHL}	Propagation Delay CP to O_N[3]	C_L = 50pF R_L = 500Ω	2.0	10.0	2.0	11.0	2.0	6.5	2.0	7.2	ns
t_{PZH} t_{PZL}	Output Enable Time		1.5	12.5	1.5	14.0	1.5	6.5	1.5	7.5	ns
t_{PHZ} t_{PLZ}	Output Disable Time		1.5	8.0	1.5	8.0	1.5	5.5	1.5	6.5	ns
t_{SU}	Set-up Time HIGH or LOW, D_N to CP		2.0	—	2.0	—	2.0	—	2.0	—	ns
t_H	Hold Time HIGH or LOW, D_N to CP		1.5	—	1.5	—	1.5	—	1.5	—	ns
t_W	CP Pulse Width HIGH or LOW		7.0	—	7.0	—	5.0	—	6.0	—	ns

3095 tbl 07

NOTES:
1. See test circuit and waveforms.
2. Minimum limits are guaranteed but not tested on Propagation Delays.
3. Propagation Delays and Enable/Disable times are with V_{CC} = 3.3V ±0.3V, Normal Range. For V_{CC} = 2.7V to 3.6V, Extended Range, all Propagation Delays and Enable/Disable times should be degraded by 20%.

TEST CIRCUITS AND WAVEFORMS

TEST CIRCUITS FOR ALL OUTPUTS



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SWITCH POSITION

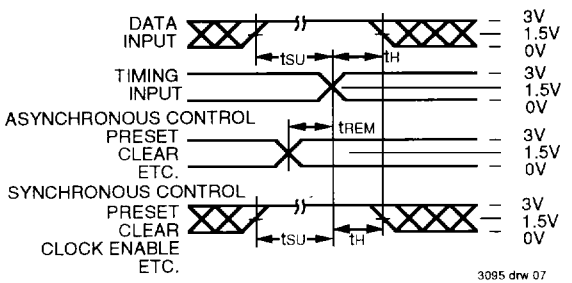
Test	Switch
Open Drain Disable Low Enable Low	6V
Disable High Enable High	GND
All Other tests	Open

3095 lnk 08

DEFINITIONS:

C_L = Load capacitance: includes jig and probe capacitance.
R_T = Termination resistance: should be equal to Z_{OUT} of the Pulse Generator.

SET-UP, HOLD AND RELEASE TIMES



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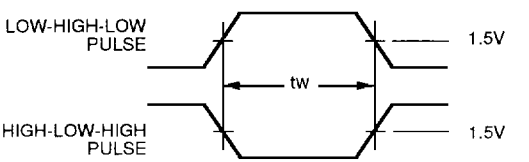
PULSE WIDTH



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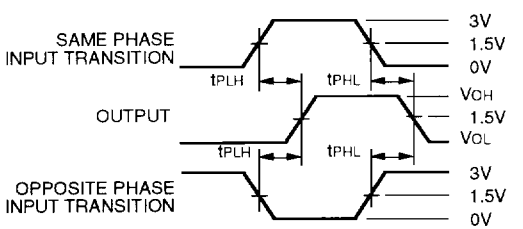
PROPAGATION DELAY



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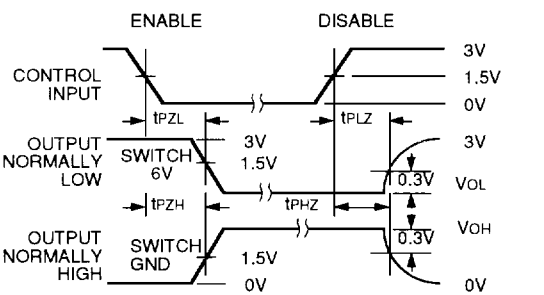
ENABLE AND DISABLE TIMES



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NOTES:

1. Diagram shown for input Control Enable-LOW and input Control Disable-HIGH.
2. Pulse Generator for All Pulses: Rate ≤ 1.0MHz; t_F ≤ 2.5ns; t_R ≤ 2.5ns.
3. If V_{CC} is below 3V, input voltage swings should be adjusted not to exceed V_{CC}.

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ORDERING INFORMATION